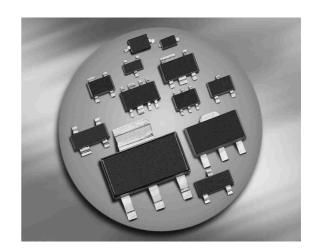


Silicon Schottky Diodes

- For low-loss, fast-recovery, meter protection, bias isolation and clamping application
- Guard ring protected
- Low forward voltage



BAT54

BAT54-04

BAT54-05

BAT54-06









Туре	Package	Configuration	L _S (nH)	Marking
BAT54*	SOT23	single	1.8	Т
BAT54-04*	SOT23	series	1.8	TS
BAT54-05*	SOT23	common cathode	1.8	тс
BAT54-06*	SOT23	common anode	1.8	TA

^{*} Preliminary data

Maximum Ratings at $T_A = 25^{\circ}$ C, unless otherwise specified

Parameter	Symbol	Value	Unit
Diode reverse voltage	V_{R}	30	V
Forward current	I _F	200	mA
Non-repetitive peak surge forward current $(t \le 10 \text{ ms})$	I _{FSM}	600	
Repetitive peak forward current ¹⁾	I _{FRM}	300	mA
$t_{\rm p} \le 1 {\rm s}, \delta = 0.5$			
Total power dissipation	P _{tot}		mW
BAT54, <i>T</i> _S ≤ 93 °C		230	
BAT54-04, <i>T</i> _S ≤ 70 °C		230	
BAT54-05, <i>T</i> _S ≤ 47 °C		230	
BAT54-06, <i>T</i> _S ≤ 70 °C		230	
Junction temperature	T _i	150	°C
Storage temperature	T _{stg}	-65 150	



Thermal Resistance

Parameter	Symbol	Value	Unit
Junction - soldering point ²⁾	R _{thJS}		K/W
BAT54		≤ 245	
BAT54-04		≤ 345	
BAT54-05		≤ 445	
BAT54-06		≤ 345	

Electrical Characteristics at $T_A = 25$ °C, unless otherwise specified

Parameter	Symbol		Values		
		min.	typ.	max.	
DC Characteristics	·				
Breakdown voltage ³⁾	$V_{(BR)}$	30	-	-	V
$I_{(BR)} = 10 \ \mu A$					
Reverse current ³⁾	I _R	-	-	2	μA
V _R = 25 V					
Forward voltage ³⁾	V _F				mV
$I_{\rm F} = 0.1 {\rm mA}$		_	_	240	
I _F = 1 mA		-	-	320	
I _F = 10 mA		-	-	400	
I _F = 30 mA		-	-	500	
$I_{\rm F}$ = 100 mA		-	-	800	
AC Characteristics			·	<u> </u>	
Diode capacitance	C _T	-	-	10	pF
$V_{R} = 1 \text{ V}, f = 1 \text{ MHz}$					
Reverse recovery time	t _{rr}	-	-	5	ns
$I_{\rm F}$ = 10 mA, $I_{\rm R}$ = 10 mA, measured $I_{\rm R}$ = 1 mA ,					
$R_{L} = 100 \Omega$					

 $^{^{1}}$ Device mounted on epoxy PCB 40 x 40 x 1.5 mm / 6 cm 2 Cu

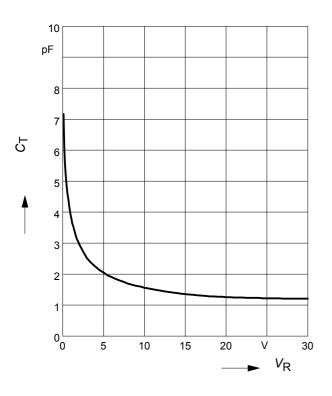
 $^{^{2}\}mbox{For calculation of}\,R_{\mbox{\scriptsize thJA}}$ please refer to Application Note Thermal Resistance

 $^{^{3}}$ Pulsed test: t_{p} = 300 µs; D = 0.01



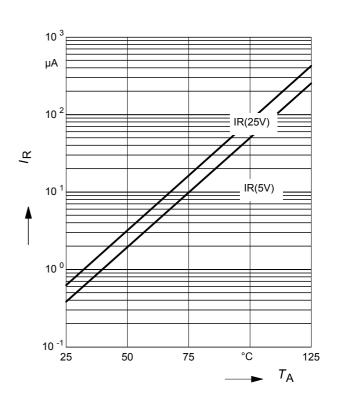
Diode capacitance $C_T = f(V_R)$

f = 1MHz



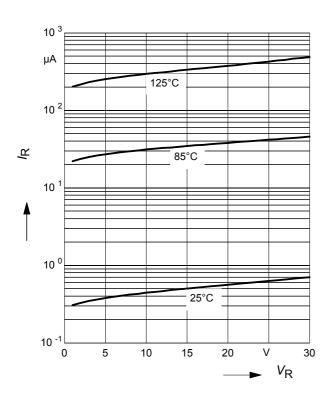
Reverse current $I_R = f(T_A)$

 V_{R} = Parameter



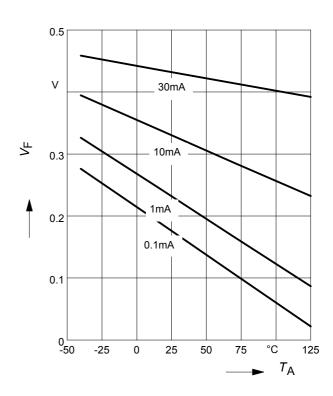
Reverse current $I_R = f(V_R)$

 T_A = Parameter



Forward Voltage $V_F = f(T_A)$

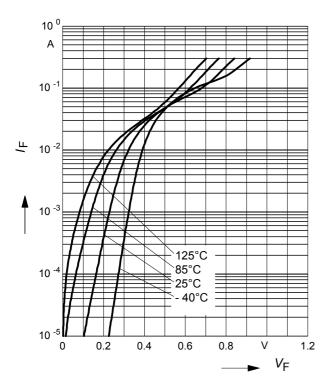
 I_{F} = Parameter



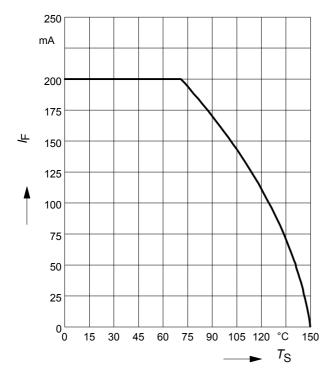


Forward current $I_F = f(V_F)$

 T_A = Parameter

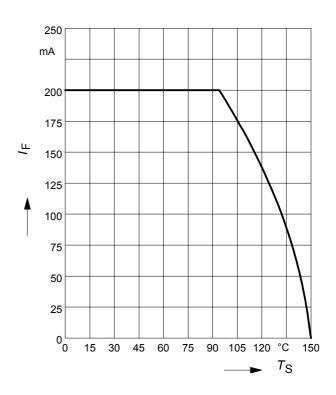


Forward current $I_F = f(T_S)$ BAT54-04, BAT54-06



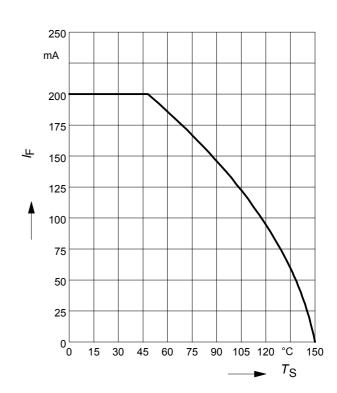
Forward current $I_F = f(T_S)$

BAT54



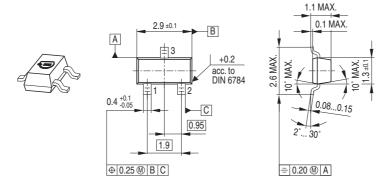
Forward current $I_F = f(T_S)$

BAT54-05

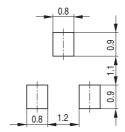




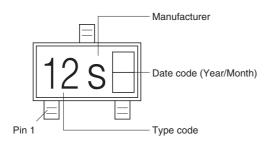
Package Outline

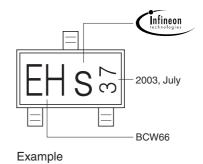


Foot Print



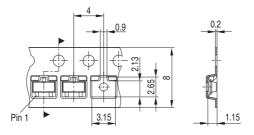
Marking Layout





Packing

Code E6327: Reel ø180 mm = 3.000 Pieces/Reel Code E6433: Reel ø330 mm = 10.000 Pieces/Reel





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